## SN54ABT5402A, SN74ABT5402A 12-BIT LINE/MEMORY DRIVERS WITH 3-STATE OUTPUTS

SCBS660B - FEBRUARY 1996 - REVISED MAY 1997

- **Output Ports Have Equivalent 25-** $\Omega$  Series **Resistors, So No External Resistors Are** Required
- State-of-the-Art *EPIC*-II*B*<sup>™</sup> BiCMOS Design Significantly Reduces Power Dissipation
- Latch-Up Performance Exceeds 500 mA Per **JEDEC Standard JESD-17**
- Typical V<sub>OLP</sub> (Output Ground Bounce) < 1 V • at V<sub>CC</sub> = 5 V, T<sub>A</sub> =  $25^{\circ}$ C
- Typical V<sub>OLV</sub> (Output Undershoot) < 0.5 V at  $V_{CC} = 5 V, T_A = 25^{\circ}C$
- **Package Options Include Plastic** Small-Outline (DW) Package and Ceramic Chip Carriers (FK) and DIPs (JT)

#### description

These 12-bit buffers and line drivers are designed specifically to improve both the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters.

The 3-state control gate is a 2-input AND gate with active-low inputs so that if either output-enable (OE1 or OE2) input is high, all 12 outputs are in the high-impedance state.

The outputs, which are designed to source or sink up to 12 mA, include equivalent 25- $\Omega$  series resistors to reduce overshoot and undershoot.

To ensure the high-impedance state during power up or power down,  $\overline{OE}$  should be tied to V<sub>CC</sub> through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

	03	μ.	5			
	D3 D2 D1 Y1 Y2 Y3 Y4	þ	6			
	D1	þ	7			
	Y1	þ	8			
	Y2	þ	9			
	Y3	Б	1(	)		
	Y4	Б	11			
		Γ		12	13	14
		-				
				≻	$\succ$	GND
						0
over the full m				em	pe	rat
from -40°C t	o 85	;°(	С.			

The SN54ABT5402A is characterized for operation of ture range of -55°C to 125°C. The SN74ABT5402A is characterized for operation from

FUNCTION TABLE								
	INPUTS	OUTPUT						
OE1	OE2	D	Y					
L	L	L	L					
L	L	Н	н					
н	Х	Х	Z					
Х	Н	Х	Z					

FUNCTION TABLE



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SN54ABT5402A.	JT PACKAGE
SN74ABT5402A.	DW PACKAGE
(TOP \	/IEW)

Y1 [ Y2 [	1	28	D1
Y2 L Y3 [	2 3	27 26	D2 D3
Y4 [	4	25	D4
Y5 [	5	24	D5
Y6 [	6	23	D6
GND [	7	22	D7
Y7 [	8	21	V <sub>CC</sub>
Y8 [	9	20	D8
Y9 [	10	19	D9
Y10 [	11	18	D10
Y11 [	12	17	D11
Y12 🛛	13	16	D12
OE1	14	15	OE2

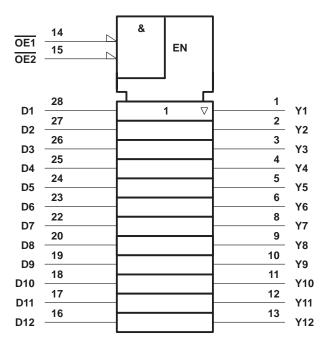
4    3    2    1    28    27    26      D3    5    25    D10      D2    6    24    D11      D1    7    23    D12      Y1    8    22    OE2      Y2    9    21    OE1
4    3    2    1    28    27    26      D3    5    25    D10      D2    6    24    D11      D1    7    23    D12      Y1    8    22    OE2
$\begin{array}{cccccccccccccccccccccccccccccccccccc$

SN54ABT5402A . . . FK PACKAGE

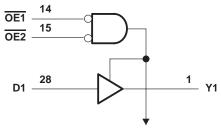
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SCBS660B - FEBRUARY 1996 - REVISED MAY 1997

#### logic symbol<sup>†</sup>



### logic diagram (positive logic)



**To Eleven Other Channels** 

<sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for the DW and JT packages.

#### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>‡</sup>

Supply voltage range, V <sub>CC</sub> Input voltage range, V <sub>I</sub> (see Note 1)	
Voltage range applied to any output in the high or power-off state, $V_{O}$	
Current into any output in the low state, $I_O$	
Input clamp current, $I_{IK}$ (V <sub>I</sub> < 0)	
Output clamp current, $I_{OK}$ ( $V_O < 0$ )	
Package thermal impedance, $\theta_{JA}$ (see Note 2): DW package	
Storage temperature range, T <sub>stg</sub>	

Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

2. The package thermal impedance is calculated in accordance with EIA/JEDEC Std JESD51.



### recommended operating conditions (see Note 3)

		s				SN74ABT5402A	
			MIN	MAX	MIN	MAX	UNIT
VCC	Supply voltage		4.5	5.5	4.5	5.5	V
VIH	IH High-level input voltage				2		V
VIL	/IL Low-level input voltage					0.8	V
VI	Input voltage		0 0	Vcc	0	VCC	V
ЮН	High-level output current		C,	-12		-12	mA
IOL	Low-level output current			12		12	mA
$\Delta t/\Delta v$	Input transition rise or fall rate	Outputs enabled	22	10		10	ns/V
Т <sub>А</sub>	Operating free-air temperature		-55	125	-40	85	°C

NOTE 3: Unused inputs must be held high or low to prevent them from floating.

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		T <sub>A</sub> = 25°C			SN54ABT5402A		SN74ABT5402A			
				MIN	TYP†	MAX	MIN	MAX	MIN	MAX	UNIT	
VIK		V <sub>CC</sub> = 4.5 V,	I <sub>I</sub> = -18 mA			-1.2		-1.2		-1.2	V	
		V <sub>CC</sub> = 4.5 V,	$I_{OH} = -1 \text{ mA}$	3.35	3.7		3.3		3.35			
		$V_{CC} = 5 V,$	$I_{OH} = -1 \text{ mA}$	3.85	4.2		3.8		3.85		V	
Vон	V <sub>CC</sub> = 4.5 V	I <sub>OH</sub> = -3 mA				3		3.1		v		
		VCC = 4.5 V	$I_{OH} = -12 \text{ mA}$	2.6					2.6			
VOL		V <sub>CC</sub> = 4.5 V	I <sub>OL</sub> = 8 mA					0.8		0.65	V	
VOL		VCC = 4.5 V	I <sub>OL</sub> = 12 mA							0.8	V V	
V <sub>hys</sub>					100						mV	
Ц		$V_{CC} = 5.5 V, V_{I} = V_{C}$	CC or GND			±1		±1		±1	μΑ	
IOZH		V <sub>CC</sub> = 5.5 V,	$V_{O} = 2.7 V$			10		10		10	μΑ	
IOZL		V <sub>CC</sub> = 5.5 V,	$V_{O} = 0.5 V$			-10		-10		-10	μΑ	
l <sub>off</sub>		$V_{CC} = 0,$	$V_{I} \text{ or } V_{O} \leq 4.5 \text{ V}$			±100	4	22		±100	μΑ	
ICEX		V <sub>CC</sub> = 5.5 V, V <sub>O</sub> = 5.5 V	Outputs high			50	UC7	50		50	μΑ	
lO		V <sub>CC</sub> = 5.5 V,	$V_{O} = 2.5 V$	-25	-45	-100	25	-100	-25	-100	mA	
los‡		V <sub>CC</sub> = 5.5 V,	$V_{O} = 0$	-50		-200	<b>2</b> –50	-200	-50	-200	mA	
		V <sub>CC</sub> = 5.5 V,	Outputs high		5	50		50		50	μA	
ICC		$I_{O} = 0,$	Outputs low		39	48		48		48	mA	
		$V_{I} = V_{CC}$ or GND	Outputs disabled		1	50		50		50	μΑ	
∇ICC§	Data inputs $V_{CC} = 5.5 \text{ V}$ , One input at 3.4 V, Other inputs at V <sub>CC</sub> or GND	$V_{CC} = 5.5 V$ , One input at 3.4 V,	Outputs enabled			1.5		1.5		1.5		
			Outputs disabled			0.05		0.05		0.05	mA	
	Control inputs	$V_{CC}$ = 5.5 V, One input at 3.4 V, Other inputs at $V_{CC}$ or GND				1.5		1.5		1.5		
Ci		$V_{I} = 2.5 \text{ V or } 0.5 \text{ V}$			3						pF	
Co		$V_{O} = 2.5 \text{ V or } 0.5 \text{ V}$			8						pF	

<sup>†</sup> All typical values are at  $V_{CC} = 5$  V.

<sup>‡</sup>Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

§ This is the increase in supply current for each input that is at the specified TTL voltage level rather than V<sub>CC</sub> or GND.

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switching characteristics over recommended ranges of supply voltage and operating free-air temperature,  $C_L = 50 \text{ pF}$  (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V( Tj	CC = 5 V A = 25°C	', ;	SN54AB1	5402A	SN74ABT	5402A	UNIT
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	
<sup>t</sup> PLH	D	Y	2	4.5	5.2	2	6.3	2	6.2	00
<sup>t</sup> PHL	D		1.5	3.7	5	1.5	5.7	1.5	5.6	ns
<sup>t</sup> PZH	OE	V	2.5	5.7	7.6	2.5	8.8	2.5	8.7	200
<sup>t</sup> PZL	OE	ř	2	4.4	6.3	3	7.6	2	7.5	ns
<sup>t</sup> PHZ	OE		1.5	3.6	4.4	1.5	5.5	1.5	5.2	
<sup>t</sup> PLZ	UE	T	1.5	4.2	5.4	<b>2</b> 1.5	7.4	1.5	6.9	ns

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7 V  $\cap$ **S1** O Open **500** Ω From Output TEST **S1**  $(\Lambda \Lambda)$ **Under Test** GND Open tPLH/tPHL C<sub>L</sub> = 50 pF 7 V **500** Ω tPLZ/tPZL (see Note A) Open tPHZ/tPZH LOAD CIRCUIT 3 V **Timing Input** 1.5 V 0 V t<sub>su</sub> th 3 V **Data Input** 1.5 V 1.5 V 0 V **VOLTAGE WAVEFORMS** SETUP AND HOLD TIMES 3 V 3 V Output 1.5 V 1.5 V Input 1.5 V 1.5 V Control 0 V 0 V <sup>t</sup>PZL - tPHL <sup>t</sup>PLH Output <sup>t</sup>PLZ VOH 3.5 V Waveform 1 1.5 V 1.5 V 1.5 V Output S1 at 7 V V<sub>OL</sub> + 0.3 V VOL VOL (see Note B) <sup>t</sup>PHZ **t**PLH tPHL -<sup>t</sup>PZH Output ٧он ٧он Waveform 2 V<sub>OH</sub> – 0.3 V 1.5 V 1.5 V 1.5 V Output S1 at Open ≈ 0 V VOL (see Note B) **VOLTAGE WAVEFORMS VOLTAGE WAVEFORMS PROPAGATION DELAY TIMES ENABLE AND DISABLE TIMES** INVERTING AND NONINVERTING OUTPUTS LOW- AND HIGH-LEVEL ENABLING

PARAMETER MEASUREMENT INFORMATION

NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
  C. All input pulses are supplied by generators having the following characteristics: PRR ≤ 10 MHz, Z<sub>Q</sub> = 50 Ω, t<sub>f</sub> ≤ 2.5 ns. t<sub>f</sub> ≤ 2.5 ns.
- D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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